

## 1. Product Information

Supplier : JIANGSU CHANGJING ELECTRONICS TECHNOLOGY CO.,LTD.

<b>Part Number:</b>	CJP039SN25MK
<b>Package Type:</b>	TO-220-3L-CB
<b>Report Date:</b>	April-2026

## 2. Reference Standard

Item	Standards
1.Human-Body Model(HBM)	JESD22-A114
2.Machine Model(MM)	JESD22-A115

## 3. Classification Criteria

HBM Classification level	
Level	Test Voltage
CLASS 0	$\leq 250V$
CLASS 1A	$> 250V$ to $\leq 500V$
CLASS 1B	$> 500V$ to $\leq 1000V$
CLASS 1C	$> 1000V$ to $\leq 2000V$
CLASS 2	$> 2000V$ to $\leq 4000V$
CLASS 3A	$> 4000V$ to $\leq 8000V$
CLASS 3B	$> 8000V$

MM Classification level	
Level	Test Voltage
CLASS A	$< 200V$
CLASS B	$\geq 200V$ to $< 400V$
CLASS C	$\geq 400V$

## 4. Test Result

Test Item	Test Condition	Samples	Class Level
HBM	Interval:1s 3Times /200V~8000V step:200V( $\pm$ )	5PCS	CLASS 1C
MM	Interval:1s 3Times /200V~800V step:200V( $\pm$ )	5PCS	CLASS C

### Notes:

The failure criterion for the ESD test is based on whether the Device Under Test (DUT) meets its product specification (datasheet). Specifically, after being subjected to the specified ESD pulse stress, the device must undergo electrical parameter testing and functional checks. The device shall be considered failed if any of the following conditions occur:

- 1) Electrical parameters deviate from the limits specified in the datasheet;
- 2) Logic functions or preset functions cannot be realized.

Remark: JSCJ Laboratory reserves the right of final interpretation of this report